

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Applicant: Sergey Velichko et al.

Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

Docket No.: 303.750US1

Serial No.: 09/834,751

Filed: April 13, 2001

Due Date: August 12, 2004

Examiner: Craig Steven Miller

Group Art Unit: 2857

Mail Stop Amendment

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450


We are transmitting herewith the following attached items (as indicated with an "X"):

- ☒ A return postcard.
- ☒ An Amendment and Response (15 Pages).
- ☒ A Communication Concerning Related Applications (1 pg.).
- ☒ A Supplemental Information Disclosure Statement (1 pg.), Form 1449 (1 pg.), and copies of 11 cited documents.
- ☒ Permission of charge Deposit Account No. 19-0743 in the amount of \$180.00 to cover the fee for consideration of Information Disclosure Statement under 97(c).

If not provided for in a separate paper filed herewith, Please consider this a **PETITION FOR EXTENSION OF TIME** for sufficient number of months to enter these papers and please charge any additional fees or credit overpayment to Deposit Account No. 19-0743.

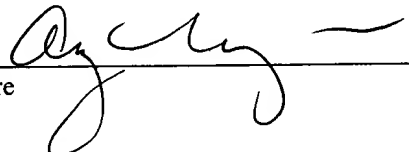
SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

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By: 
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Reg. No. 42,267

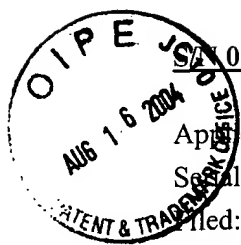
CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 12th day of August, 2004.

Amy Moriarty
Name


Signature

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

(GENERAL)



09/834,751

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COMMUNICATION CONCERNING RELATED APPLICATION(S)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Applicants would like to bring to the Examiner's attention the following related application(s) in the above-identified patent application:

<u>Serial/Patent No.</u>	<u>Filing Date</u>	<u>Attorney Docket</u>	<u>Title</u>
10/131934	April 25, 2002	303.771US1	INTELLIGENT MEASUREMENT MODULAR SEMICONDUCTOR PARAMETRIC TEST SYSTEM
10/133685	April 25, 2002	303.821US1	DYNAMICALLY ADAPTABLE SEMICONDUCTOR PARAMETRIC TESTING
10/417640	April 17, 2003	303.855US1	DYNAMIC CREATION AND MODIFICATION OF WAFER TEST MAPS DURING WAFER TESTING

Respectfully submitted,

SERGEY A. VELICHKO ET AL.

By Applicants' Representatives,

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Date

August 12, 2004

By

Suneel Arora

Reg. No. 42,267

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Name

Amy Moriarty

Signature